Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/009,239	BAE ET AL.	
Examiner	Art Unit	
Duy M. Dang	2624	

	SEARCHED				
Class	Subclass	Date	Examiner		
382	128 130-133 232-233	7/7/2006	DD		
	240 244				
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378	4 8				
705	3				
707	204	V	V		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (uspto, pgpub, derwent, jpo, epo) see printouts	7/7/2006	DD		
Inventor search (east), see printouts				
IEEE search, see printout	J	V		